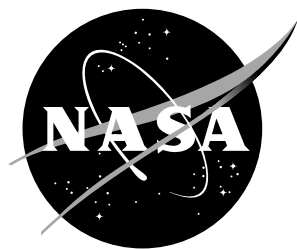


NASA/TM-2018-219809



Determination of Cross-Sectional Area of Focused Picosecond Gaussian Laser Beam

*Rodolfo Ledesma and James Fitz-Gerald
University of Virginia, Charlottesville, Virginia*

*Frank Palmieri and John Connell
Langley Research Center, Hampton, Virginia*

February 2018

NASA STI Program... in Profile

Since its founding, NASA has been dedicated to the advancement of aeronautics and space science. The NASA scientific and technical information (STI) program plays a key part in helping NASA maintain this important role.

The NASA STI Program operates under the auspices of the Agency Chief Information Officer. It collects, organizes, provides for archiving, and disseminates NASA's STI. The NASA STI Program provides access to the NASA Aeronautics and Space Database and its public interface, the NASA Technical Report Server, thus providing one of the largest collections of aeronautical and space science STI in the world. Results are published in both non-NASA channels and by NASA in the NASA STI Report Series, which includes the following report types:

- **TECHNICAL PUBLICATION.** Reports of completed research or a major significant phase of research that present the results of NASA programs and include extensive data or theoretical analysis. Includes compilations of significant scientific and technical data and information deemed to be of continuing reference value. NASA counterpart of peer-reviewed formal professional papers, but having less stringent limitations on manuscript length and extent of graphic presentations.
- **TECHNICAL MEMORANDUM.** Scientific and technical findings that are preliminary or of specialized interest, e.g., quick release reports, working papers, and bibliographies that contain minimal annotation. Does not contain extensive analysis.
- **CONTRACTOR REPORT.** Scientific and technical findings by NASA-sponsored contractors and grantees.

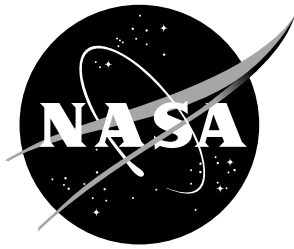
- **CONFERENCE PUBLICATION.** Collected papers from scientific and technical conferences, symposia, seminars, or other meetings sponsored or co-sponsored by NASA.
- **SPECIAL PUBLICATION.** Scientific, technical, or historical information from NASA programs, projects, and missions, often concerned with subjects having substantial public interest.
- **TECHNICAL TRANSLATION.** English-language translations of foreign scientific and technical material pertinent to NASA's mission.

Specialized services also include organizing and publishing research results, distributing specialized research announcements and feeds, providing information desk and personal search support, and enabling data exchange services.

For more information about the NASA STI Program, see the following:

- Access the NASA STI program home page at <http://www.sti.nasa.gov>
- E-mail your question to help@sti.nasa.gov
- Phone the NASA STI Information Desk at 757-864-9658
- Write to:
NASA STI Information Desk
Mail Stop 148
NASA Langley Research Center
Hampton, VA 23681-2199

NASA/TM-2018-219809



Determination of Cross-Sectional Area of Focused Picosecond Gaussian Laser Beam

*Rodolfo Ledesma and James Fitz-Gerald
University of Virginia, Charlottesville, Virginia*

*Frank Palmieri and John Connell
Langley Research Center, Hampton, Virginia*

National Aeronautics and
Space Administration

Langley Research Center
Hampton, Virginia 23681-2199

February 2018

Acknowledgments

The authors acknowledge funding from the NASA Advanced Composites Project.

The use of trademarks or names of manufacturers in this report is for accurate reporting and does not constitute an official endorsement, either expressed or implied, of such products or manufacturers by the National Aeronautics and Space Administration.

Available from:

NASA STI Program / Mail Stop 148
NASA Langley Research Center
Hampton, VA 23681-2199
Fax: 757-864-6500

Abstract

Measurement of the waist diameter of a focused Gaussian-beam at the $1/e^2$ intensity, also referred to as spot size, is key to determining the fluence in laser processing experiments. Spot size measurements are also helpful to calculate the threshold energy and threshold fluence of a given material. This work reports an application of a conventional method, by analyzing single laser ablated spots for different laser pulse energies, to determine the cross-sectional area of a focused Gaussian-beam, which has a nominal pulse width of ~ 10 ps. Polished tungsten was used as the target material, due to its low surface roughness and low ablation threshold, to measure the beam waist diameter. From the ablative spot measurements, the ablation threshold fluence of the tungsten substrate was also calculated.

1 Introduction

The characterization of laser systems is important for understanding the effects of the laser parameters (e.g. wavelength, pulse duration, and spot size) on the ablation mechanisms. The ablation mechanism of a given material can occur by photothermal, photochemical, or photophysical ablation, and generally depends on the wavelength and pulse duration of the laser beam. Different ablation mechanisms will produce different characteristics in the ablation damage, given the type of substrate, e.g. metals and polymers. The properties of a substrate determine how the irradiated light interacts with the surface and how the light is absorbed. In order to compare results found in the literature, which report threshold fluences given a specific substrate and laser characteristics, it is key to determine the spot size and consequently, the cross-sectional area of the focused laser beam. Fluence is an important parameter and is calculated as the amount of energy irradiated on a surface per unit area. Several reports in the literature have addressed the determination of Gaussian laser beam spot size [1–5], even for two-dimensional energy distribution [6].

In this work, the area of a focused Gaussian picosecond laser beam is determined by exposure of ultraviolet single-shot laser pulses on a tungsten substrate. A conventional method [3, 4] is employed to measure the one-dimensional diameter of the beam waist ($1/e^2$) by analyzing single laser ablated spots for different laser pulse energies. The results include the measurements of the dimensions of the ablated craters. The ablation threshold of tungsten is determined by single-shot picosecond laser pulses.

2 Experimental

2.1 Materials

Tungsten polycrystalline substrate (MTI Corp.) was used for the determination of the focused laser beam area. The tungsten substrate had two sides polished, nominal purity of 99.95%, and nominal average surface roughness of less than 30

Å. The surface characteristics of the tungsten substrate provided a homogeneous surface to clearly measure the ablated crater dimensions.

2.2 Laser Ablation

The schematic diagram of the laser system is shown in Figure 1. The single-shot ablation was performed with a Nd:YVO₄ (Atlantic 20-355, EKSPLA) laser, which was operated at 355 nm with a nominal pulse duration of ~ 10 ps. The laser beam was focused by an f-theta lens (S4LFT6062/075, Sill Optics), with an effective focal length of 250 mm, for a wavelength of 355 nm. The laser source operates at TEM₀₀ beam mode. The TEM₀₀ laser beam passes through optical components before being focused by the f-theta lens. The laser system was assembled and calibrated by PhotoMachining Inc. The average laser power was measured with a thermopile sensor (30A-BB-18, Ophir-Spiricon) and a laser power meter (Nova II, Ophir-Spiricon). The laser ablated spots were produced by moving the XY translational stage to expose a fresh surface after each single laser shot.

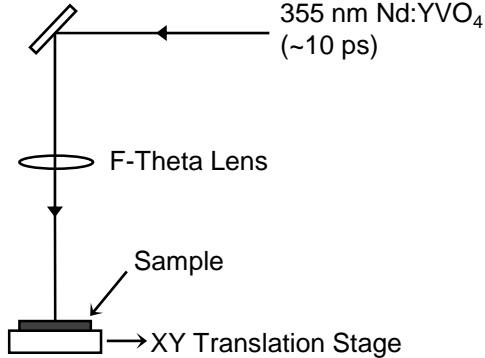


Figure 1. Schematic of the picosecond laser system for ablation of the tungsten sample.

2.3 Ablation Spot Analysis

The surface morphology analysis was performed using a JEOL JSM-5600 scanning electron microscope (SEM) operated at an accelerating voltage of 15 kV. The dimensions of the ablated spots were measured by analyzing the SEM micrographs using the image processing and analysis software ImageJ [7].

3 Results and Discussion

Figure 2 shows the SEM micrographs of the ablation craters for the pulse energies of 5 μJ , 15 μJ , and 30 μJ . The contours of the ablated craters exhibit smooth edges. This demonstrates that there is no thermal damage or redeposited material around the craters. As the laser energy increases, the shape of the ablated crater diverges from an ellipse. In addition, the absorption of the laser pulse at the center

increases and produces an inner crater with a more consistent elliptical shape. The inner crater can be evidently observed in Figure 2c. The inner crater in Figure 2c also presents smooth edges. Above 15 μJ , the craters exhibit a deformation, which may be due to a distortion in the spatial laser energy distribution. The contours of ablated craters exhibit effects of astigmatism, which produces an elliptical shape. Different angles of divergence in two transverse directions cause astigmatism and elliptical beams [8–10]. Despite the drawback of the crater shapes ablated above 15 μJ , Figure 3 shows the closest elliptical fit to the crater contours. Figure 3a shows that the ablated crater was easily fit, however in Figures 3b and 3c, the elliptical fits became more challenging. From the elliptical fit (red contour) shown in Figure 3, consider D_1 as the minor diameter (green chord) and D_2 the major diameter (yellow chord).

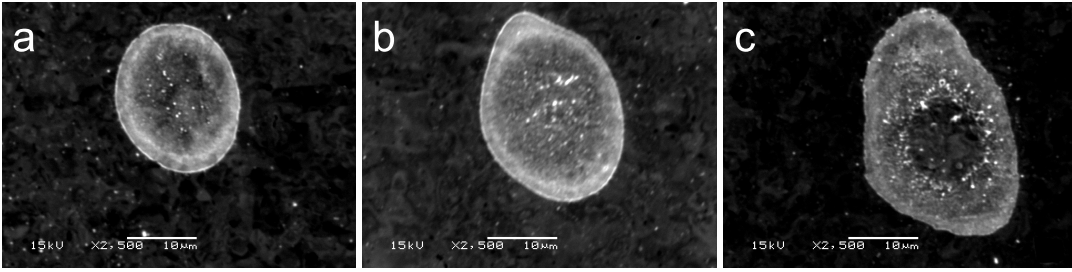


Figure 2. SEM micrographs of craters ablated at a) 5 μJ , b) 15 μJ , and c) 30 μJ .

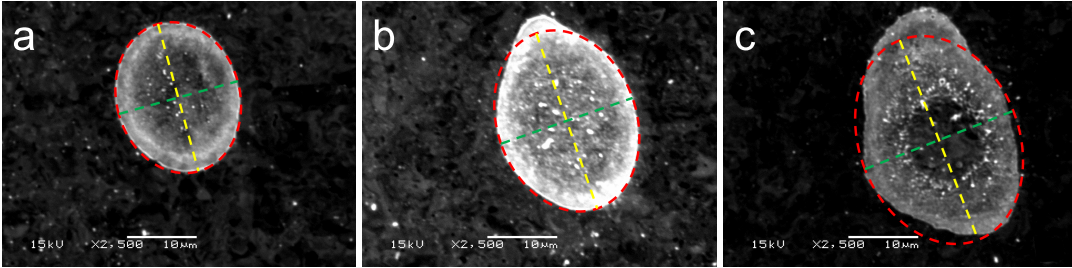


Figure 3. SEM micrographs with measurements of the elliptical fits to ablated crater contours, a) 5 μJ , b) 15 μJ , and c) 30 μJ . The green chord is the minor diameter, and the yellow chord is the major diameter.

Theoretically, the diameter of an ablated spot can be calculated by [11]:

$$D^2 = \frac{D_0^2}{2} \ln \left(\frac{E}{E_{th}} \right) \quad (1)$$

where D is the diameter of the ablated crater, D_0 the diameter at the Gaussian beam waist, E the irradiated pulse energy on the material, and E_{th} the ablation threshold of the material. The optical diameter D_0 represents $1/e^2$ of the intensity peak value. Within the circle of radius $w(z)$, 86% of the laser beam power is carried. At the waist, $z = 0$, the radius is $w(0) = D_0/2$.

From the SEM micrographs, it is clear that the Gaussian beam distribution is two-dimensional. Considering the minor diameter axis to be x and the major axis to be y , the two-dimensional Gaussian intensity (irradiance) at the beam waist is given by:

$$I(x, y) = I_0 \exp\left(-\frac{2x^2}{w_{0x}^2}\right) \exp\left(-\frac{2y^2}{w_{0y}^2}\right) \quad (2)$$

where I_0 is the peak intensity at the center of the beam and w_0 is the Gaussian beam radius, at which the intensity drops to $1/e^2$ of its peak intensity. The peak of the two-dimensional Gaussian function occurs when both radial positions, x and y , are on the center axis of the beam, i.e. $(x, y) = (0, 0)$.

Figure 4 shows the single-shot laser ablation threshold measurements of tungsten. Each data point is an average of three measurements, and the error bars indicate 1σ standard deviation. The logarithm of the ratio of E to E_{th} is linearly proportional to D^2 . From the logarithmic fit to D_1 , $E_{th,1} = 0.34 \mu\text{J}$. Likewise, for D_2 , $E_{th,2} = 0.8 \mu\text{J}$. Since the threshold for D_1 is smaller than that for D_2 , D_1 is used to determine the ablation threshold energy, E_{th} , needed to produce ablation damage on the tungsten substrate. Therefore, $D_0 = D_1 = 2w_{0x}$. Consequently, $E_{th} = E_{th,1} = 0.34 \mu\text{J}$.

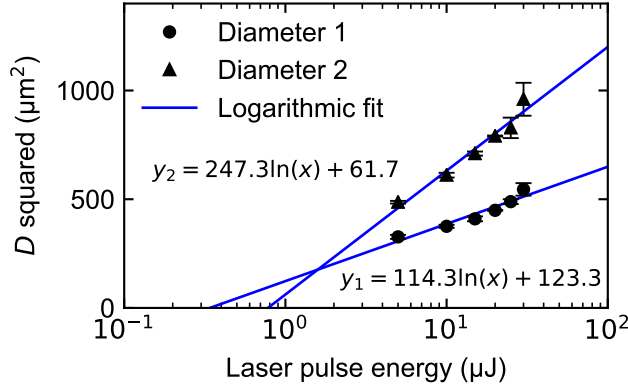


Figure 4. Single-shot laser ablation threshold measurements of tungsten. Diameter 1 is referred to as D_1 , the minor diameter, and Diameter 2 is referred to as D_2 , the major diameter.

Figure 5 shows the linear relationship between $\ln(E/E_{th})$ and D^2 , according to Eq. 1. From Eq. 1, the one-dimensional optical diameter of the Gaussian beam can be determined when $D = D_0$, and consequently $E/E_{th} = e^2$. Considering the minor diameter, when $D_1 = D_{1,0} = 15.1 \mu\text{m}$, E_1 equals $2.5 \mu\text{J}$. Now, calculating for D_2 at $E_1 = 2.5 \mu\text{J}$ yields $D_2 = 16.8 \mu\text{m}$. The cross-sectional area A of the focused elliptical laser beam is calculated as:

$$A = \left(\frac{\pi}{4}\right) D_1 D_2 \quad (3)$$

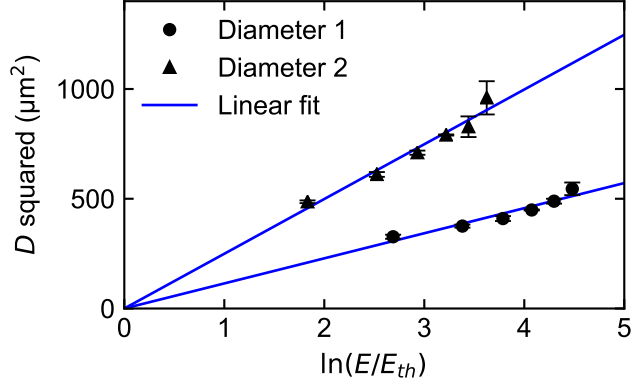


Figure 5. Linear relationship between $\ln(E/E_{th})$ and D_2 , according to Eq. 1.

Therefore, the elliptical area A is $1.99 \times 10^{-6} \text{ cm}^2$. By knowing the focused laser beam area, the average fluence F can be calculated as:

$$F = \frac{E}{A} \quad (4)$$

and the peak fluence as:

$$F = \frac{2E}{A} \quad (5)$$

Thus, the threshold fluence of the tungsten substrate using the ~ 10 ps focused laser beam is 0.17 J/cm^2 . This fluence threshold is similar to other values found in literature [12–15].

4 Conclusions

The one-dimensional spot size of the Gaussian beam at the waist was determined. The ablated spots were generated using single laser pulses focused on a tungsten substrate. The focused Gaussian beam generated ablative damage in an elliptical shape. Thus, the Gaussian beam was represented with a two-dimensional spatial distribution. The minor diameter of the elliptical fit of the ablated crater contour was used to determine the energy and fluence thresholds. Using picosecond pulses, the threshold energy of tungsten was found to be $0.34 \text{ }\mu\text{J}$, and the cross-sectional area of the focused elliptical laser beam was determined as $1.99 \times 10^{-6} \text{ cm}^2$. Thus, the threshold fluence was calculated to be 0.17 J/cm^2 .

References

1. Winer, I.: A self-calibrating technique measuring laser beam intensity distributions. *Appl. Opt.*, vol. 5, 1966, pp. 1437–1439.

2. Mauck, M.: Knife-edge profiling of Q-switched Nd:YAG laser beam and waist. *Appl. Opt.*, vol. 18, 1979, pp. 599–600.
3. Liu, J.: Simple technique for measurements of pulsed Gaussian-beam spot sizes. *Opt. Lett.*, vol. 7, 1982, pp. 196–198.
4. Kiang, Y.; and Lang, R.: Measuring focused Gaussian beam spot sizes: A practical method. *Appl. Opt.*, vol. 22, 1983, pp. 1296–1297.
5. Krüger, J.; and Kautek, W.: Ultrashort pulse laser interaction with dielectrics and polymers. *Adv. Polym. Sci.*, vol. 168, 2004, pp. 247–289.
6. Lednev, V.; Pershin, S.; Obraztsova, E.; Kudryashov, S.; and Bunkin, A.: Single-shot and single-spot measurement of laser ablation threshold for carbon nanotubes. *J. Phys. D: Appl. Phys.*, vol. 46, 2013, p. 052002.
7. Rasband, W.: ImageJ. <http://imagej.nih.gov/ij/>, 1997–2016.
8. Roichman, Y.; Waldron, A.; Gardel, E.; and Grier, D.: Optical traps with geometric aberrations. *Appl. Opt.*, vol. 45, 2006, pp. 3425–3429.
9. Sun, H.: Laser diode beam basics. *A Practical Guide to Handling Laser Diode Beams*, Springer Netherlands, 2015, pp. 27–51.
10. Alda, J.: Laser and Gaussian beam propagation and transformation. *Encyclopedia of Optical and Photonic Engineering*, C. Hoffman and R. Driggers, eds., CRC Press, 2015, pp. 1–15.
11. Haskal, H.; and Rosen, A.: Power and focusing considerations for recording with a laser beam in the TEM₀₀ mode. *Appl. Opt.*, vol. 10, 1971, pp. 1354–1358.
12. Preuss, S.; Demchuk, A.; and Stuke, M.: Sub-picosecond UV laser ablation of metals. *Appl. Phys. A*, vol. 61, 1995, pp. 33–37.
13. Byskov-Nielsen, J.; Savolainen, J.-M.; Christensen, M.; and Balling, P.: Ultra-short pulse laser ablation of copper, silver and tungsten: experimental data and two-temperature model simulations. *Appl. Phys. A*, vol. 103, 2011, pp. 447–453.
14. Sniukasa, R.; and Raciukaitis, G.: Laser micro-cutting of thick tungsten sheets. *Lasers in Manufacturing Conference*, 2015.
15. Pfeifenberger, M.; Mangang, M.; Wurster, S.; Reiser, J.; Hohenwarter, A.; Pflöging, W.; Kiener, D.; and Pippan, R.: The use of femtosecond laser ablation as a novel tool for rapid micro-mechanical sample preparation. *Mater. Des.*, vol. 121, 2017, pp. 109–118.

REPORT DOCUMENTATION PAGE				Form Approved OMB No. 0704-0188	
<p>The public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number.</p> <p>PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS.</p>					
1. REPORT DATE (DD-MM-YYYY) 01-02-2018		2. REPORT TYPE Technical Memorandum		3. DATES COVERED (From - To)	
4. TITLE AND SUBTITLE Determination of Cross-Sectional Area of Focused Picosecond Gaussian Laser Beam			5a. CONTRACT NUMBER		
			5b. GRANT NUMBER		
			5c. PROGRAM ELEMENT NUMBER		
6. AUTHOR(S) Rodolfo Ledesma, Frank Palmieri, James Fitz-Gerald, and John Connell			5d. PROJECT NUMBER		
			5e. TASK NUMBER		
			5f. WORK UNIT NUMBER 826611.04.07.03		
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) NASA Langley Research Center Hampton, Virginia 23681-2199			8. PERFORMING ORGANIZATION REPORT NUMBER L-20906		
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) National Aeronautics and Space Administration Washington, DC 20546-0001			10. SPONSOR/MONITOR'S ACRONYM(S) NASA		
			11. SPONSOR/MONITOR'S REPORT NUMBER(S) NASA/TM-2018-219809		
12. DISTRIBUTION/AVAILABILITY STATEMENT Unclassified-Unlimited Subject Category 23 Availability: NASA STI Program (757) 864-9658					
13. SUPPLEMENTARY NOTES An electronic version can be found at http://ntrs.nasa.gov .					
14. ABSTRACT Measurement of the waist diameter of a focused Gaussian-beam at the $1/e^2$ intensity, also referred to as spot size, is key to determining the fluence in laser processing experiments. Spot size measurements are also helpful to calculate the threshold energy and threshold fluence of a given material. This work reports an application of a conventional method, by analyzing single laser ablated spots for different laser pulse energies, to determine the cross-sectional area of a focused Gaussian-beam, which has a nominal pulse width of ~ 10 ps. Polished tungsten was used as the target material, due to its low surface roughness and low ablation threshold, to measure the beam waist diameter. From the ablative spot measurements, the ablation threshold fluence of the tungsten substrate was also calculated.					
15. SUBJECT TERMS Gaussian beam, Spot size, Picosecond, Laser ablation, Scanning electron microscopy					
16. SECURITY CLASSIFICATION OF:			17. LIMITATION OF ABSTRACT	18. NUMBER OF PAGES	19a. NAME OF RESPONSIBLE PERSON
a. REPORT	b. ABSTRACT	c. THIS PAGE			STI Information Desk (help@sti.nasa.gov)
U	U	U	UU	11	19b. TELEPHONE NUMBER (Include area code) (757) 864-9658